



Scanning Near Field Optical Microscopes probes-without tuning forks-wavelength 600-770nm

SNF_OMP-c

AFM Nanoprobes SNOM probes stand up to the most demanding applications, including infrared and UV/visible range. Our tips are made of high-quality polymers and also come in a variety of coatings to support your testing and imaging needs. Material – single mode optical fiber Nufern 630HP.

Probe tip is coated by Al (70nm)/sublayer V (20nm) .

Tip diameter uncoated by Al (tip aperture) 100 – 150 nm (125±25)

Angle of fiber – about 20 degrees

Maximum optical input power – 400 microWatt

The probes are prepared by chemical etching method.

This method gives the optical efficiency 10² – 10⁴ times better than those obtained by mechanical pulling. GEOMETRICAL & MECHANICAL FIBER SPECIFICATIONS: SNOM PROBE CHARACTERISTICS:

SPECIFICATIONS

short_desc	SNOM probes (wavelength 600-770nm) for Scanning Near Field Optical Microscopes, without tuning forks
Quantity	10
Coating	Al Reflective
Cantilever	Single
Tip Material	Single mode optical fiber (Basic Nufern fiber)